

Notice of References Cited	Application/Control No. 10/730,638	Applicant(s)/Patent Under Reexamination TAKEISHI ET AL.	
	Examiner Cam N. Nguyen	Art Unit 1754	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-3,554,930	01-1971		502/342
*	D	US-3,661,806	05-1972		502/313
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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